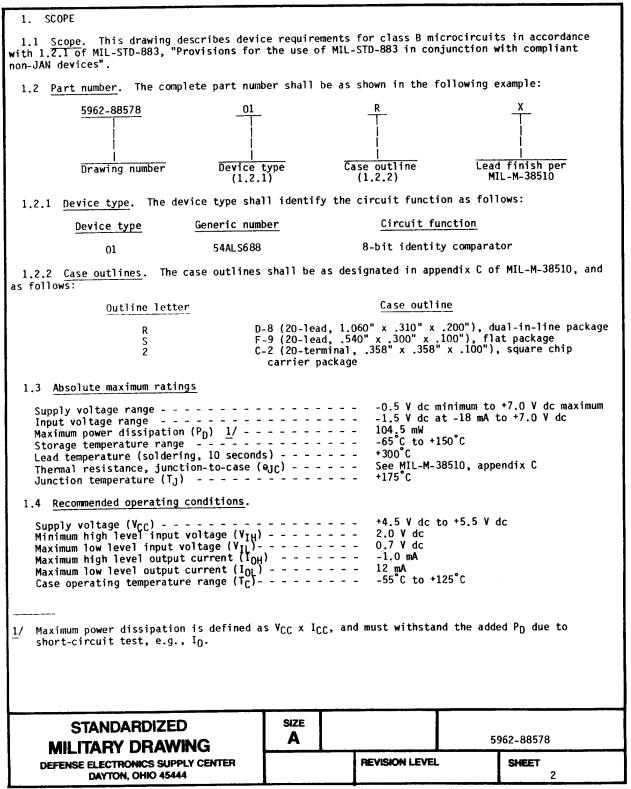
REVISIONS																									
LTR						ı	DESC	RIP	ΠON				-		¥			DAT	E (YR	- <b>M</b> O-0	DA)	A	PPRO	OVED	
REV																									
SHEET																									
REV													L	<u> </u>		<u> </u>	_	<u> </u>	<u> </u>	_		_		_	Щ
SHEET	لبا			L,				<u> </u>		<u> </u>	1_		_	↓_		_	_		_	<u> </u>	_	<u> </u>	<u> </u>	<u> </u>	lacksquare
REV STATUS OF SHEETS	-	RE			H	٦		<u>_</u>	_	-	,			10		_	$\vdash$			<u> </u>	_	-		$\vdash$	$\vdash$
PMIC N/A		SH	EET		PRE	2 PARE	3 ED BY	4_	5	6	16		9	10	DEF	ENS							NTE	R R	
STANDA MILIT DRAV	VIN	Y G			CHECKED BY  CHECKED BY  APPROVED BY  DRAWING APPROVACIONE				71	DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444  MICROCIRCUITS, DIGITAL, BIPOLAR, ADVANCE LOW POWER SCHOTTKY TTL, 8-BIT IDENTITY COMPARATOR, MONOLITHIC SILICON				ANCE TY	D										
THIS DRAWING FOR USE BY AL AND AGEN DEPARTMEN	L DEF	PARTI	MENT IE	rs	1	6 M	AY 1	988		ATE			$\int$	SIZE			372				59	62	-8	85	78
AMSC N/A	THE VISION LEVEL					SHE	ET		1 .		OF		10												

DESC FORM 193 SEP 87

 $\circ$  U.S. Government printing office: 1987 — 748-129/60911  $5962\!-\!E809$ 



## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

### REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 <u>Truth table</u>. The truth table shall be as specified on figure 2.
- 3.2.3 Test circuit and switching waveforms. The test circuit and switching waveforms shall be as specified on figure 3.
  - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A
5962-88578

REVISION LEVEL
SHEET
3

DESC FORM 193A SEP 87

TABLE I. Electrical performance characteristics.							
Test	Symbol	Conditions   -55°C < T <sub>C</sub> < +125°C   unless otherwise specified	Group A	Lim		Unit	
High level output voltage	I V <sub>OH</sub>	$ V_{CC}  = 4.5 \text{ V} \qquad V_{IH} = 2.0 \text{ V}$ $ V_{IL}  = 0.7 \text{ V} \qquad I_{OH} = -0.4 \text{ mA}$	1,2,3	2.5		V	
Low level output voltage	v <sub>OL</sub>	$V_{CC} = 4.5 \text{ V}$ $V_{IH} = 2.0 \text{ V}$ $V_{IL} = 0.7 \text{ V}$ $I_{OL} = 12 \text{ mA}$	1,2,3		0.4	٧	
Input clamp voltage	\v_{1C}	V <sub>CC</sub> = 4.5 V I <sub>IN</sub> = -18 mA	1,2,3		  -1.5 	٧	
Low level input current	1	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 0.4 V	1,2,3		-0.1	mA	
High level input current	1	$V_{CC} = 5.5 \text{ V}$ $V_{IN} = 2.7 \text{ V}$ $V_{CC} = 5.5 \text{ V}$ $V_{IN} = 7.0 \text{ V}$	1,2,3		20 100	μА	
Output current	I <sub>0</sub>	V <sub>CC</sub> = 5.5 V V <sub>OUT</sub> = 2.25 V	1,2,3	-30	-112	mA	
Power supply current	Icc	V <sub>CC</sub> = 5.5 V	1,2,3		19	mA	
Functional testing	İ	  See 4.3.1c 	7,8				
Propagation delay time, P to $P = Q$	tpHI 1	V <sub>CC</sub> = 4.5 V to 5.5 V C <sub>L</sub> = 50 pF ± 10% R <sub>L</sub> = 500Ω ± 5% See figure 3	9,10,11	5	16 25	ns	
Propagation delay time, Q to $P = Q$	t <sub>PLH2</sub>		9,10,11	3 5	16 25	ns	
Propagation delay time, $G$ to $P = Q$	t <sub>PLH3</sub>		9,10,11	3	15 25	ns	

<sup>1/</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current,  $\rm I_{OS}$ . Not more than one ouput should be shorted at a time and the duration of the short circuit condition should not exceed one second.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A
5962-88578

REVISION LEVEL
SHEET
4

DESC FORM 193A SEP 87

- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be Tisted as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
  - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test, method 1015 of MIL-STD-883.
    - (1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_{\Delta} = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method  $\overline{5005}$  of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, and 6 in table 1, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroup 7 and 8 tests shall verify the truth table as specified on figure 2 herein.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady state life test conditions, method 1005 of MIL-STD-883:
      - (1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125$ °C, minimum.
      - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARDIZED MILITARY DRAWING	SIZE <b>A</b>		5962-88578			
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVE	-	SHEET 5		

Cases R, S, and 2							
Terminal connection	Terminal symbol						
1	G						
2	P0						
3	QO						
4	P1						
5	Q1						
6	P2						
7	Q2						
8	Р3						
9	Q3						
10	GND						
11	P4						
12	Q4						
13	P5						
14	Q5						
15	P6						
16	Q6						
17	P7						
18	Q7						
19	P = Q						
20	v <sub>CC</sub>						

FIGURE 1. Terminal connections.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A

5962-88578

FEVISION LEVEL
SHEET 6

Connection	Description
P0 - P7	Data inputs
Q0 - Q7	Data inputs
G	Enable input
P = Q	Output

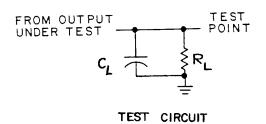
FIGURE 1. Terminal connections - Continued.

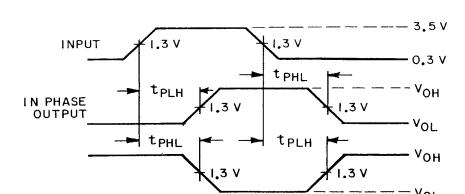
Inpu	Output	
Data   P, Q	Enable   G	P = Q
P = Q	L	L
P > Q	L	H H
P < Q	L L	H
T X	H H	Н

H = High voltage level steady state
L = Low voltage level steady state
X = Irrelevant

FIGURE 2. Truth table.

STANDARDIZED MILITARY DRAWING	SIZE <b>A</b>		5962-88578
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 7





PROPAGATION DELAY TIMES

# NOTES:

- 1. CL includes probe and jig capacitance.
- 2. All input pulses have the following characteristics: PRR  $\leq$  10 MHz, duty cycle = 50%, tr = tf = 3 ns ±1 ns.
- 3. The outputs are measured one at a time with one input transition per measurement.

FIGURE 3. Test circuit and switching waveforms.

# STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 SIZE A 5962-88578 REVISION LEVEL SHEET 8

# TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table 1)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 8   9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

<sup>\*</sup> PDA applies to subgroup 1.

# 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

## 6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

STANDARDIZED

MILITARY DRAWING

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A

REVISION LE

5962-88578

REVISION LEVEL SHEET
9

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor     CAGE     number	Vendor similar part number <u>1</u> /
5962-8857801RX	01295	SNJ54ALS688J
5962-8857801SX	01295	SNJ54ALS688W
5962-88578012X	01295	SNJ54ALS688FK

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

01295

Vendor name and address

Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79701

STANDARDIZED MILITARY DRAWING

DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444

DESC FORM 193A SEP 87

# U. S. GOVERNMENT PRINTING OFFICE: 1988-549-904